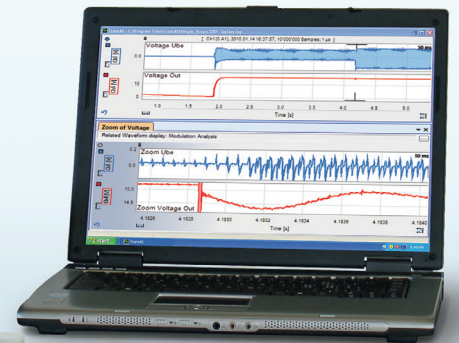
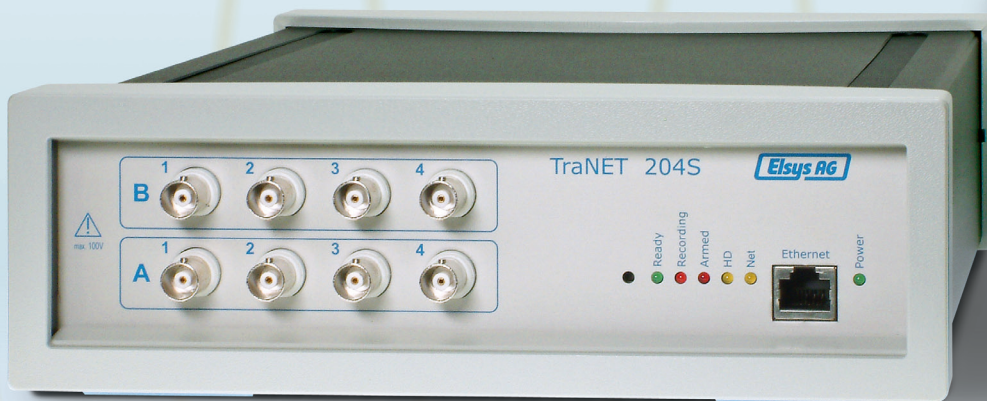


We look closer!

# Elsys TraNET® FE

## Front-End Data Acquisition Instrument

The LAN connected TraNET FE instrument turns your computer into a powerful Data Acquisition System



- Turnkey Instruments
- up to 240 MS/s @ 14-bit, 60 MS/s @ 16-bit
- up to 32-ch SE, 16-ch DIFF



# TraNET FE

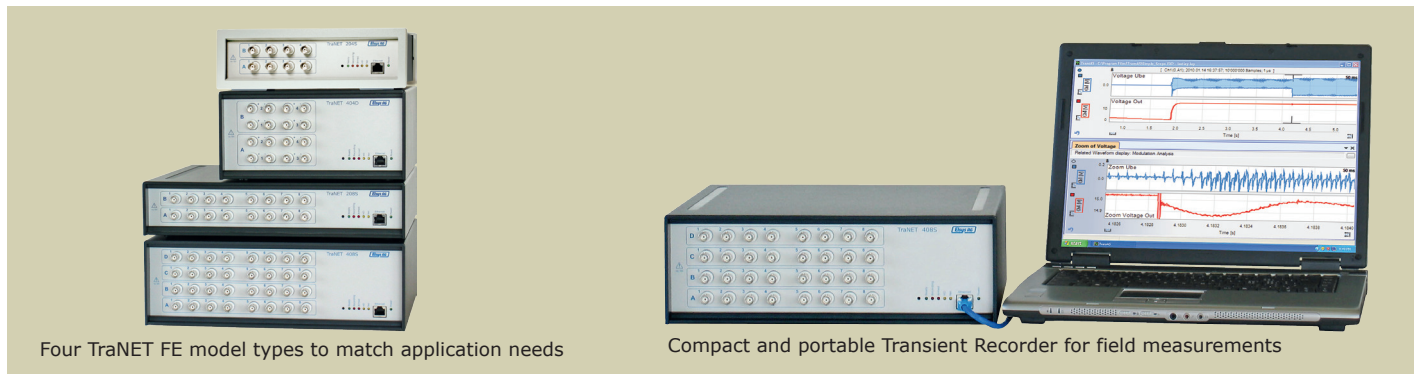
The family of modular TraNET data acquisition instruments provides turnkey solutions to many complex measurement problems. Because the TraNET data acquisition systems are flexible, compact and portable, they can be used to solve in situ problems in automotive, power generation, transportation and train systems. The powerful triggering, deep memory, and versatile front end capability also solves prob-

lems in debug and verification of electronic and mechanical designs. The TraNET system allows you to monitor a remote engine via LAN, or verify and test an injection system. With the Continuous Data Recorder mode, a long duration event can be stored to disk, gap free in real-time, and analyzed later. If applications require complex triggering across many channels, TraNET can help you capture sequential blocks of data, without any loss, using

the unique ECR Event Controlled Recording mode. For trouble-shooting applications, TraNET features an advanced trigger mode that allows triggering on anomalies and events difficult to capture and visualize otherwise. The powerful application software TransAS not only helps to quickly configure many acquisition channels, but also provides the right post-processing tools to analyze complex waveforms.

## Key Capabilities

- LAN based Data Acquisition Device
- Remote control for setup, recording, and data retrieval
- Stand alone operation for remote unattended capture of elusive signals
- Up to 32-channels SE, 16-channels differential
- Systems with up to 512 channels
- Up to 240 MS/s sample rate
- Up to 16-bit resolution
- Up to 128 MS acquisition memory per channel
- High-precision typ. 0.03% of FSR
- Continuous data recording
- Multiblock data acquisition mode
- Unique Event Controlled Recording (ECR) mode to overlap multiblocks
- Dual sample rate recording
- Flexible parallel triggering mode using all channels and advanced trigger for debugging
- TransAS with more than 50 scalar functions and built in Formula Editor with more than 60 math. functions for advanced waveform analysis
- Built in Macro language
- Digital inputs (Markers) for monitoring synchronized with analog signals
- IVI-Driver with sample programs for C++/C#, VB and LabView



## TraNET FE Standard Models

| Model Base Unit | Model Extension <sup>1)</sup> | # of Channels  | Max. Sample Rate/ch [MS/s]         | ADC Resolution (16-bit up to 1/4 of max. sample rate) |          | Memory [MS/ch]               |                               |
|-----------------|-------------------------------|----------------|------------------------------------|---|----------|------------------------------|-------------------------------|
|                 |                               |                |                                    | Standard  | Optional | Standard                     | Optional                      |
| TraNET 204      | -1x4S/ff/bb                   | 4 SE, 2 Diff   | 10<br>20<br>40<br>80<br>120<br>240 | 14-bit  | 16-bit   | 16 MS<br>32 MS <sup>2)</sup> | 64 MS<br>128 MS <sup>2)</sup> |
|                 | -1x4D/ff/bb                   | 4 Diff         |                                    |   |          |                              |                               |
|                 | -2x4S/ff/bb                   | 8 SE, 4 Diff   |                                    |   |          |                              |                               |
| TraNET 404      | -2x4D/ff/bb                   | 8 Diff         | 10<br>20                           | 14-bit  | 16-bit   | 8 MS                         | 32 MS                         |
|                 | -3x4S/ff/bb                   | 12 SE, 6 Diff  |                                    |   |          |                              |                               |
|                 | -4x4S/ff/bb                   | 16 SE, 8 Diff  |                                    |   |          |                              |                               |
| TraNET 208      | -1x8S/ff/bb                   | 8 SE, 4 Diff   | 10<br>20                           | 14-bit  | 16-bit   | 8 MS                         | 32 MS                         |
|                 | -1x8D/ff/bb                   | 8 Diff         |                                    |   |          |                              |                               |
|                 | -2x8S/ff/bb                   | 16 SE, 8 Diff  |                                    |   |          |                              |                               |
| TraNET 408      | -2x8D/ff/bb                   | 16 Diff        | 10<br>20                           | 14-bit  | 16-bit   | 8 MS                         | 32 MS                         |
|                 | -3x8S/ff/bb                   | 24 SE, 6 Diff  |                                    |   |          |                              |                               |
|                 | -4x8S/ff/bb                   | 32 SE, 16 Diff |                                    |   |          |                              |                               |

1) Replace "ff" with Max. Sample Rate and "bb" with ADC Resolution. Example: TraNET 404-3x4S/40/16 -> 12-ch single ended, 40 MS/s, 16-bit

2) Sample rates 120 MS/s, 240 MS/s only